

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/707,762	YIN ET AL.	
Examiner	Art Unit	
Tae H. Yoon	1714	

SEARCHED					
Class	Subclass	Date	Examiner		
527 523	47 116 112	9-16-06	w		
523	116				
	112				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST Inventor Search	9-16-06	T		